

## **Distinguished Lecturer Program – 2013 Call for Applications**

The Instrumentation and Measurement (I&M) Society is currently accepting applications for new Distinguished Lecturers (DL) for the Distinguished Lecturer Program (DLP). The DLP provides I&M chapters and technical events around the world with talks by experts on topics of interest and importance to the I&M community. Our lecturers are among the most qualified experts in their field. More details on the DLP can be found at: <http://www.ieee-ims.org/education/distinguished-lecturers-program>.

DLP Evaluations for 2013 will take place in May at I<sup>2</sup>MTC in Minneapolis, MN. Details on the Evaluation Meeting will be made available on the I&M website (<http://www.ieee-ims.org/>) and the I<sup>2</sup>MTC website (<http://imtc.ieee-ims.org/>) when available.

Suggested topics for DL presentations include (but are not limited to):

- Laser/Optics (including Fiber Optic Sensing),
- Measurement Precision, Sensitivity, and Noise
- DC Measurements
- Biomedical Instrumentation and Measurements
- Robotics/Automated Measurements
- Nanotechnology in Instrumentation and Measurement
- State-of-the-Art of Traditional Measurements and Instrumentation (Digitizers, Voltmeters, Spectrum Analyzers, etc.).

To apply, submit a Word 2003 (or later) file and include the following:

- Title of Presentation
- Presenter's name and affiliation
- Abstract of the presentation topic (between 500 and 1000 words)
- A biography of the presenter (limited to 150 words)

Applications will be accepted through midnight (CST) on April 29<sup>th</sup>, 2013. Proposal presentations selected for an evaluation slot must be *must be no longer* than 12 minutes.

For questions or to submit your application, contact the DLP Chair, Kristen Donnell, at [kristen.donnell@mst.edu](mailto:kristen.donnell@mst.edu).